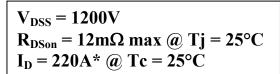
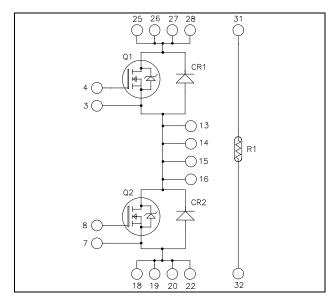


### Phase leg SiC MOSFET Power Module





# **Application**

- Welding converters
- Switched Mode Power Supplies
- Uninterruptible Power Supplies
- Motor control

#### **Features**

#### SiC Power MOSFET

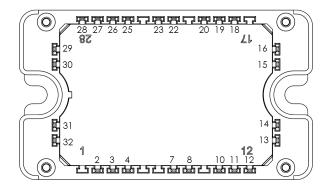
- High speed switching
- Low R<sub>DS(on)</sub>
- Ultra low loss

#### SiC Schottky Diode

- Zero reverse recovery
- Zero forward recovery
- Temperature Independent switching behavior
- Positive temperature coefficient on VF
- Very low stray inductance
- Kelvin source for easy drive
- Internal thermistor for temperature monitoring
- High level of integration
- AlN substrate for improved thermal performance



- Outstanding performance at high frequency operation
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Solderable terminals both for power and signal for easy PCB mounting
- Low profile
- **RoHS Compliant**



Pins 25 to 28 must be shorted together Pins 13 to 16 must be shorted together Pins 18/19/20/22 must be shorted together

All ratings @  $T_i = 25$ °C unless otherwise specified

CAUTION: These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed. See application note APT0502 on www.microsemi.com



### Absolute maximum ratings (per SiC MOSFET)

Symbol	Parameter		Max ratings	Unit
$V_{ m DSS}$	Drain - Source Voltage		1200	V
ī	Continuous Drain Current	$T_c = 25$ °C	220*	
$I_D$	Continuous Drain Current	$T_c = 80$ °C	165*	Α
$I_{DM}$	Pulsed Drain current		440	
$V_{GS}$	Gate - Source Voltage		-10/25V	V
$R_{DSon}$	Drain - Source ON Resistance		12	mΩ
$P_{D}$	Maximum Power Dissipation	$T_c = 25^{\circ}C$	925	W

<sup>\*</sup> Specification of device but current must be limited due to size of pins.

### **Electrical Characteristics** (per SiC MOSFET)

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit	
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{GS} = 0V$ , $V_{DS} = 1200V$				300	μA
D	Drain – Source on Resistance	$V_{GS} = 20V$	$T_j = 25^{\circ}C$		8	12	
$R_{DS(on)}$		$I_{\rm D} = 150 A$	$T_j = 150$ °C		14	21	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 30 \text{mA}$		2.1	2.4		V
$I_{GSS}$	Gate – Source Leakage Current	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				1.8	μA

### **Dynamic Characteristics** (per SiC MOSFET)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
$C_{iss}$	Input Capacitance	$V_{GS} = 0V$			8.4		
$C_{oss}$	Output Capacitance	$V_{DS} = 1000V$			0.66		nF
$C_{rss}$	Reverse Transfer Capacitance	f = 1MHz			0.045		
$Q_{g}$	Total gate Charge	$V_{GS} = -5/+20V$			483		
$Q_{\mathrm{gs}}$	Gate – Source Charge	$V_{Bus} = 800V$			138		nC
$Q_{gd}$	Gate – Drain Charge	$I_{\rm D} = 150 A$			150		
$T_{d(on)}$	Turn-on Delay Time	$V_{} = 5/+20V$	$V_{GS} = -5/+20V$ $V_{Bus} = 800V$ $I_D = 150A$ , $T_J = 150$ °C		35		
$T_{\rm r}$	Rise Time	0.0			40		
$T_{d(off)}$	Turn-off Delay Time	- , ,			150		ns
$T_{\mathrm{f}}$	Fall Time	$R_L = 5.3\Omega$ ; $R_{Gext} = 0$	5.7Ω		70		
Eon	Turn on Energy	Inductive Switching $V_{GS} = -5/+20V$ $V_{Bus} = 600V$	$T_{j} = 150^{\circ}C$		3.3		mJ
E <sub>off</sub>	Turn off Energy	$I_{D} = 150A$ $R_{Gext} = 6.7\Omega$	$T_{j} = 150^{\circ}C$		1.8		1113
$R_{Gint}$	Internal gate resistance				2		Ω
$R_{\text{thJC}}$	Junction to Case Thermal Resistar	nce				0.135	°C/W

### **Body diode ratings and characteristics** (per SiC MOSFET)

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
$ m V_{SD}$	Diode Forward Voltage	$V_{GS} = -5V, I_{SD} = 75A$		3.3		V
	Diode Folward Voltage	$V_{GS} = -2V, I_{SD} = 75A$		3.1		V
t <sub>rr</sub>	Reverse Recovery Time			45		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$I_{SD} = 150A$ ; $V_{GS} = -5V$ $V_{R} = 800V$ ; $di_{F}/dt = 3000A/\mu s$		1.2		μC
$I_{rr}$	Reverse Recovery Current	γ <sub>R</sub> 300 γ , αι <sub>Γ</sub> /αι 3000 Α/μ3		40		A

2 - 8



### SiC schottky diode ratings and characteristics (per SiC diode)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
$V_{RRM}$	Peak Repetitive Reverse Voltage					1200	V
T	Input   Reverse Leakage Current   Vp=1200V	V -1200V	$T_j = 25$ °C		105	600	^
1 <sub>RRM</sub>		$T_j = 175$ °C		195	1200	μA	
$I_F$	DC Forward Current		Tc = 125°C		60		A
$V_{\mathrm{F}}$	Diode Forward Voltage	$I_r = 60\Delta$	$T_i = 25$ °C		1.5	1.8	V
V F			$T_i = 175^{\circ}C$		2.2	3	v
Qc	Total Capacitive Charge	$I_F = 60A, V_R = 1200V$ $di/dt = 1500A/\mu s$			390		nC
С	Total Campaitance	$f = 1 MHz, V_R = 400V$ $f = 1 MHz, V_R = 800V$			279		рF
	Total Capacitance				201		pF
$R_{thJC}$	Junction to Case Thermal Resistance					0.37	°C/W

### Temperature sensor NTC (see application note APT0406 on www.microsemi.com).

Symbol	Characteristic		Min	Typ	Max	Unit
R <sub>25</sub>	Resistance @ 25°C			50		kΩ
$\Delta R_{25}/R_{25}$				5		%
$B_{25/85}$	$T_{25} = 298.15 \text{ K}$			3952		K
$\Delta B/B$		T <sub>C</sub> =100°C		4		%

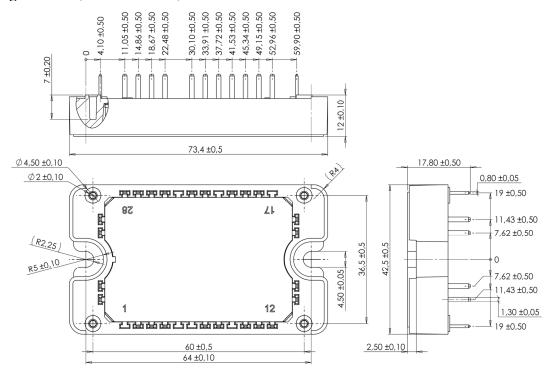
$$R_T = \frac{R_{25}}{\exp \left[ B_{25/85} \left( \frac{1}{T_{25}} - \frac{1}{T} \right) \right]} \quad \text{T: Thermistor temperature}$$
 
$$R_T: \text{ Thermistor value at T}$$

# Thermal and package characteristics

Symbol	Characteristic			Min	Max	Unit	
$V_{ISOL}$	RMS Isolation Voltage, any terminal to case t =1 min, 50/60Hz			4000		V	
$T_{J}$	Operating junction temperature range	SiC MC	OSFET	-40	150		
	Operating junction temperature range	SiC d	iode	-40	175		
$T_{JOP}$	Recommended junction temperature under switching conditions				T <sub>J</sub> max -25	°C	
$T_{STG}$	Storage Temperature Range				125		
$T_{\rm C}$	Operating Case Temperature	-40	100				
Torque	Mounting torque	To heatsink	M4	2	3	N.m	
Wt	Package Weight				110	g	
	<u> </u>	·					



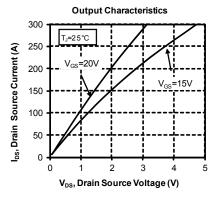
### Package outline (dimensions in mm)

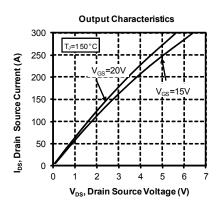


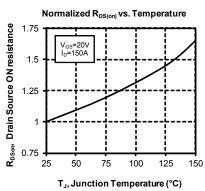
See application note 1906 - Mounting Instructions for SP3F Power Modules on www.microsemi.com

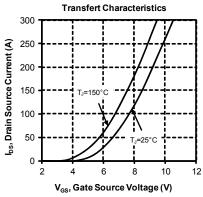


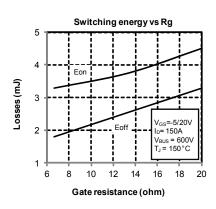
### **Typical SiC MOSFET Performance Curve**

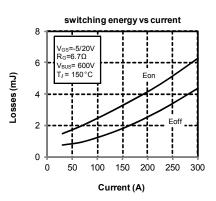


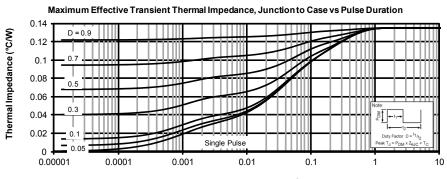








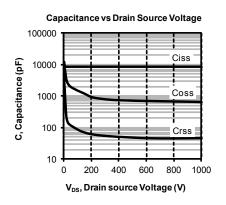


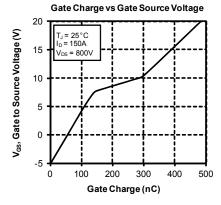


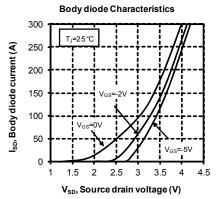
rectangular Pulse Duration (Seconds)

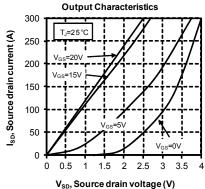
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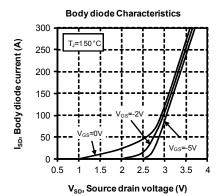


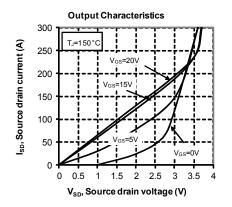


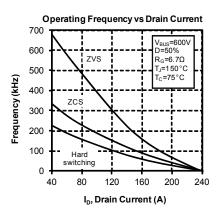








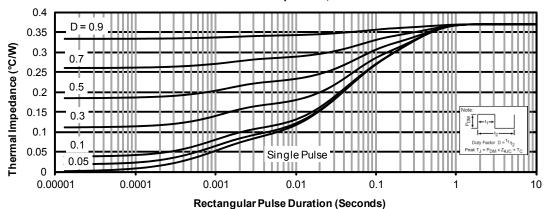


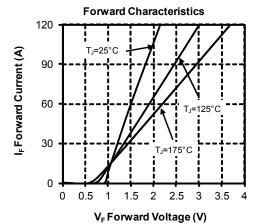


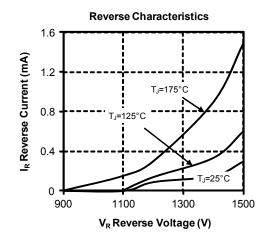


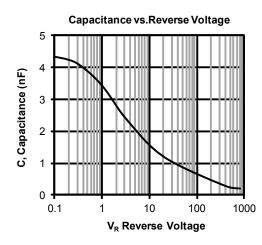
### **Typical SiC diode Performance Curve**

#### Maximum Effective Transient Thermal Impedance, Junction to Case vs Pulse Duration











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8 - 8